## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V.		PCMF3HDMI2BA-C						
Name of Laboratory Assembly reliability labs		Part Description						
		NXP ICN8 Protection INDI						
		WLCSP package						
Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
	5 1	Tj = Tjmax, Vr = 100% of max. datasheet						
# 5	Bias	reverse voltage	1000 hours	68	4040	0		
	тс	JESD22-A104						
# 7	Temperature Cycling	-40 °C to 125°C	1000 cycles	24	1440	0		
	UHAST	JESD22-A118						
# 8 <b>or</b>	Unbiased HAST	Tamb = 130 °C, RH = 85 %						
		JESD22-A102	— 96 hours	n.a.	n.a.	n.a.		
	AC	Tamb = $121 ^{\circ}C$ , RH = $100 ^{\circ}M$						
# 8a	Autoclave	Pressure = $205 \text{ kPa} (29.7 \text{ psia})$						
# 00								
	HAST	JESD22-A110						
	Highly Accelerated Stress	Tamb = 130 °C, RH = 85%, VR = 80 % of						
# 9	Test	rated reverse voltage <sup>[1]</sup>	1000 hours	24	1440	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure $\Delta T_j$ =						
# 10	Intermittent Operating Life		1000 hours	n.a.	n.a.	n.a.		
		· ·						
	RSH	JESD22-A111						
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
	SD							
# 21	Solderability	J-STD-002		n.a.	n.a.	n.a.		

[1]The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
NXP ICN8	Protection INDI	4040	0	1,1	9,51E+08

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